

<b>Notice of References Cited</b>		Application/Control No. 10/821,723	Applicant(s)/Patent Under Reexamination MERRY ET AL.	
		Examiner Patricia A. George	Art Unit 1765	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,478,766	12-1995	Park et al.	438/158
*	B	US-6,440,753	08-2002	Ning et al.	438/3
*	C	US-2002/0179248	12-2002	Kabansky, Alex	156/345.36
*	D	US-2002/0132488	09-2002	Nallan, Padmapani	438/720
*	E	US-6,440,864	08-2002	Kropewnicki et al.	438/710
*	F	US-6,283,692	09-2001	Perlov et al.	414/222.01
*	G	US-2002/0192957	12-2002	Chien et al.	438/689
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Wolf et al (Vol. 1, Process Technology, 1986, Lattice Press, figure 5, page 546-547 & pg. 432))
	V	Van Zant (A Practice Guide to Semiconductor Processing; Semiconductor Services; 1986; section 13.6, figure 13.6)
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.